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(Revision of  
IEEE Std 323™-1983)

**323™**

**IEEE Standard for Qualifying  
Class 1E Equipment for Nuclear  
Power Generating Stations**

**IEEE Power Engineering Society**

Sponsored by the  
Nuclear Power Engineering Committee



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# IEEE Standard for Qualifying Class 1E Equipment for Nuclear Power Generating Stations

Sponsor

**Nuclear Power Engineering Committee**  
of the  
**IEEE Power Engineering Society**

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**IEEE-SA Standards Board**

**Abstract:** The basic requirements for qualifying Class 1E equipment and interfaces that are to be used in nuclear power generating stations are described in this standard. The principles, methods, and procedures described are intended to be used for qualifying equipment, maintaining and extending qualification, and updating qualification, as required, if the equipment is modified. The qualification requirements in this standard, when met, demonstrate and document the ability of equipment to perform safety function(s) under applicable service conditions including design basis events, reducing the risk of common-cause equipment failure.

**Keywords:** age conditioning, aging, condition monitoring, design basis events, equipment qualification, harsh environment, margin, mild environment, qualification methods, qualified life, radiation, safety related function, significant aging mechanism, test plan, test sequence, type testing

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## Introduction

(This introduction is not part of IEEE Std 323-2003, IEEE Standard for Qualifying Class 1E Equipment for Nuclear Power Generating Stations.)

IEEE Std 323-2003, a revision of IEEE Std 323-1983, is the result of a review of IEEE Std 323-1983 and present practices in equipment qualification. This revision incorporates current practices and lessons learned from the implementation of previous versions of this standard by the nuclear industry.

Several issues are clarified or changed in this revision:

- This standard defines the methods for equipment qualification when it is desired to qualify equipment for the applications and the environments to which it may be exposed. This standard is generally utilized for qualification of Class 1E (safety-related electric) equipment located in harsh environments, and for certain post-accident monitoring equipment, but it may also be utilized for the qualification of equipment in mild environments. The documentation requirements are, however, more rigorous for equipment located in a harsh environment.
- The term *design basis event* has been generally used instead of the acronyms DBE, DBA, LOCA, and HELB, and the term *design basis accident* in order to reduce the complexity of the text.
- Seismic events are identified as design basis events.
- The test margins have been updated to better identify the parameters that achieve test margin on design basis event profiles. Since quantitative margin can be adequately identified by increases in temperature, pressure, radiation, and operating time, the performance of two transients is no longer recommended.
- New digital systems and new advanced analog systems may require susceptibility testing for EMI/RFI and power surges, if the environments are significant to the equipment being qualified. Since existing instrument and control (I&C) systems were less vulnerable and have the benefit of successful operation under nuclear power plant EMI/RFI and power surge environments, qualification to EMI/RFI and power surges was not previously significant enough to be considered in environmental equipment qualification. As existing I&C equipment in nuclear power plants may be replaced with computer-based digital I&C systems and advanced analog systems, these new technologies may exhibit greater vulnerability to the nuclear power plant EMI/RFI and power surges environments. Documents such as NUREG/CR-5900-1992 [B32],<sup>a</sup> NUREG/CR-5904-1994 [B33], NUREG/CR-6384-1996, Volumes 1 and 2 ([B34], [B35]), NUREG/CR-6406-1996 [B36], NUREG/CR-6579-1998 [37], and NRC IN-94-20 [B31] have documented the environmental influence of EMI/RFI and power surges on safety-related electric equipment. Guidelines for ensuring electromagnetic compatibility of safety systems can be found in IEEE Std 603<sup>TM</sup>-1998 and IEEE Std 7-4.3.2<sup>TM</sup>-2003.<sup>b</sup>
- An important concept in equipment qualification is the recognition that significant degradation could be caused by aging mechanisms occurring from the environments during the service life, and therefore safety-related electric equipment should be in a state of degradation prior to imposing design basis event simulations. Previous versions recognized that the period of time for which acceptable performance was demonstrated is the qualified life. The concept of qualified life continues in this revision. This revision also recognizes that the condition of the equipment for which acceptable performance was demonstrated is the qualified condition. Thus, new license renewal and life extension options are available by assuring that qualified equipment continues to remain in a qualified condition.

Industry research in the area of equipment qualification and decades of its application have greatly benefited this standard. Future activities of the working group to update this standard will consider the following:

<sup>a</sup>The numbers in brackets correspond to those of the bibliography in Annex A.

<sup>b</sup>Information on references can be found in Clause 2.

- Risk-informed approaches and impact of condition monitoring, performance, safety function assessment, and qualified life precision.
- Significance of refinements in aging mechanisms, equipment sealing, interfaces, extrapolation, similarity, test sequence and parameters (such as ramp rates, time duration, timing of spray initiation and its duration), and qualification documentation.

## Participants

This standard was prepared by Working Group (SC 2.1) of the Subcommittee on Qualification (SC 2) of the Nuclear Power Engineering Committee of the IEEE Power Engineering Society. At the time of completion, SC 2.1 had the following membership:

### James F. Gleason, *Chair*

Satish K. Aggarwal	Christopher M. Gleason	Robert J. Lofaro
Anup K. Behera	Patrick Gove	Bruce M. Lory
Thomas Brewington	Tom Hency	Edward Mohtashemi
Nissen M. Burstein	Jerrell C. Henley	Mathalie Nadeau
Mike Dougherty	David A. Horvath	Paul Shemanski
Quang H. Duong	Serena A. Jagtiani-Krause	John Wheless
Wells D. Fargo	Sushant Kapur	John White
Artur J. Faya	Byung-Ryung Koh	Michael J. Wylie
	Henry Leung	

At the time this revised standard was completed, the Nuclear Power Engineering Committee/Subcommittee on Qualification (SC 2) had the following membership:

### Satish K. Aggarwal, *Chair*

Javier Alonso	Wells D. Fargo	Todd Milton
Bohumil Bartonicek	Artur J. Faya	Edward Mohtashemi
P. D. Baughman	Robert Francis	Carole Monchy-Leroy
Anup K. Behera	James F. Gleason	Bill Newell
Brij Bharteey	Patrick Gove	James Parello
Thomas Brewington	William L. Hadovski	Janez Pavsek
Candace Brooks	Peter Helander	Daniel J. Pomerening
Rufus A. Brown	Jerrell C. Henley	John M. Richards
Nissen M. Burstein	Thomas R. Henry, III	Zoltan R. Rosztoczy
Craig E. Butler	David A. Horvath	Fred Roy
Steve Candevall	Craig S. Irish	Steve Sandberg
Garry L. Chapman	Serena A. Jagtiani-Krause	Glen E. Schinzel
Marty Chipkin	Sushant Kapur	Roderick Simms
Jeff Chivers	Mohsin Khan	Kjell Spang
Soo Y. Choi	Gene R. Kopecky	Richard G. Starck
James M. Dean	Jacob M. Kulangara	Marek Tengler
Liviu N. Delcea	Thoma Kurt	Gary Toman
Dennis E. Dellinger	Henry Leung	Marco Van Uffelen
Phillip DiBenedetto	Victor Loczi	Laszlo Varga
Quang H. Doung	Robert J. Lofaro	Carl Weber
Frank Drumm	Bruce M. Lory	John Wheless
Jeffrey S. Esterman	Darin R. Martin	John White
Keith Evans	Wolfgang Michel	Richard T. Woods
		Toshio Yamamoto

The following members of the balloting committee voted on this standard. Balloters may have voted for approval, disapproval, or abstention.

Satish K. Aggarwal  
James Anderson  
Stan J. Arnot  
George Ballassi  
Farouk Baxter  
Anup K. Behera  
Wesley Bowers  
Thomas Brewington  
Daniel Brosnan  
Rufus A. Brown  
Keith Bush  
Salvatore Carfagno  
Robert Carruth  
John Carter  
Garry V. Chapman  
John Disosway  
Surin Dureja  
Amir El-Sheikh

Wells D. Fargo  
Robert Fuld  
James F. Gleason  
Lawrence Gradin  
Britton Grim  
Randall Groves  
Ajit Gwal  
William L. Hadovski  
Philip M. Holzman  
David A. Horvath  
Peter Hung  
Paul Johnson  
Henry Leung  
Robert J. Lofaro  
John Merando  
Gary Michel  
Daleep C. Mohla  
Gerald Nicely

James Parello  
Charles Roslund  
James Ruggieri  
William Schwartz  
Neil Smith  
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Joseph Stevens  
James Stoner  
John Tanaka  
John Taylor  
James Thomas  
Gary Toman  
Michael Tucker  
John Ullo  
T. J. Voss  
John White  
Paul L. Yanosy, Sr.  
Li Zhang

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Joseph A. Bruder  
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Daleep C. Mohla  
William J. Moylan  
Paul Nikolich  
Gary S. Robinson  
Malcolm V. Thaden  
Geoffrey O. Thompson  
Doug Topping  
Howard L. Wolfman

\*Member Emeritus

Also included are the following IEEE-SA Standards Board liaisons:

Alan Cookson, *NIST Representative*  
Satish K. Aggarwal, *NRC Representative*

Savoula Amanatidis  
*IEEE Standards Managing Editor*

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## 1. Scope

This standard describes the basic requirements for qualifying Class 1E equipment and interfaces that are to be used in nuclear power generating stations. The principles, methods, and procedures described are intended to be used for qualifying equipment, maintaining and extending qualification, and updating qualification, as required, if the equipment is modified. The qualification requirements in this standard, when met, demonstrate and document the ability of equipment to perform safety function(s) under applicable service conditions including design basis events, reducing the risk of common-cause equipment failure. This standard does not provide environmental stress levels and performance requirements.

NOTE—Other IEEE standards that present qualification methods for specific equipment, specific environments, or specific parts of the qualification program may be used to supplement this standard, as applicable. Annex A lists other standards related to equipment qualification.

## 2. References

This standard shall be used in conjunction with the following standards. When the following standards are superseded by an approved version, the revision shall apply.

IEEE Std 3449™-1997 (Reaff 1993), IEEE Recommended Practice for Seismic Qualification of Class 1E Equipment for Nuclear Power Generating Stations.<sup>1,2</sup>

IEEE Std 603™-1998, IEEE Standard Criteria for Safety Systems for Nuclear Power Generating Stations.

IEEE Std 7-4.3.2™-2003, IEEE Standard Criteria for Digital Computers in Safety Systems of Nuclear Power Generating Stations.

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